## Notice of References Cited

Application/Control N 09/431,477	Reexamination	Applicant(s)/Patent Under Reexamination GANESH ET AL.		
Examiner	Art Unit			
Phallaka Kik	2825	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,308,303	10-2001	Mysore et al.	716/5
	В	US-6,308,302	10-2001	Hathaway et al.	, 716/5
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-	,		
	Н	US-			
	ı	US-			·
	J	US-		·	
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					·

## **NON-PATENT DOCUMENTS**

	NON-FAILE DOCUMENTS			
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U	Aipperspach et al. "A 0.2-/spl mu/m, 1.8V, SOI, 550-MHZ, 64-b PowerPC Micropocessor with Copper Interconnects", IEEE Journal of Solid-State Circuits, Vol. 34, No. 11, 15 February 1999, pp. 1430-1435.		
	٧	Malinoski et al., "A test site thermal control system for at-speed manufacturing testing", Proceedings of the 1998 International Test Conference, 18 October 1998, pp. 119-128.		
	w			
	х			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.